

N-Channel 60V(D-S) MOSFET

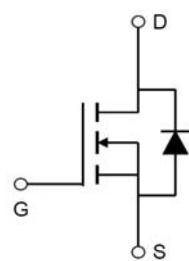
Product summary		
V_{DS}	60	V
$R_{DS(ON)}$ (at $V_{GS}=10V$) Typ.	7.5	$m\Omega$
$I_D(T_c=25^\circ C)$	55	A

Features
<ul style="list-style-type: none"> Advanced Trench Technology Low Gate Charge
Applications
<ul style="list-style-type: none"> PWM Application Load switching

Pin Configuration



TO-252



Packing Information

Device	Package	Reel Size	Quantity(Min. Package)
ECFA55N06	TO-252	13"	2500pcs

Absolute Maximum Ratings (at $T_A=25^\circ C$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	60	V
V_{GS}	Gate-Source Voltage	± 20	V
I_D	Continuous Drain Current	55	A
		34.8	A
I_{DM}	Pulse Drain Current Tested ^A	230	A
E_{AS}	Single Pulse Avalanche Energy ^B	121	mJ
P_D	Power Dissipation $T_c=25^\circ C$	58	W
T_J, T_{STG}	Junction and Storage Temperature Range	-55 to +150	$^\circ C$

Thermal Characteristics

Symbol	Parameter	Typical	Units
$R_{\theta JC}$	Thermal Resistance-Junction to case	2.16	$^\circ C/W$

Electrical Characteristics (at $T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Condition	Min.	Typ.	Max.	Units
Static Parameters						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	60	--	--	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=60\text{V}, V_{\text{GS}}=0\text{V}$	--	--	1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=\pm 20\text{V}$	--	--	± 100	nA
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	3.0	4.0	V
$R_{\text{DS}(\text{ON})}$	Drain-Source On-State Resistance ^C	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=20\text{A}$	--	7.5	9.8	$\text{m}\Omega$
Dynamic Parameters ^D						
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=25\text{V}$ $f=1\text{MHZ}$	--	2800	--	pF
C_{oss}	Output Capacitance		--	196	--	pF
C_{rss}	Reverse Transfer Capacitance		--	172	--	pF
Q_g	Total Gate Charge	$V_{\text{DS}}=30\text{V}, I_{\text{D}}=30\text{A}$ $V_{\text{GS}}=0 \text{ to } 10\text{V}$	--	85	--	nC
Q_{gs}	Gate-Source Charge		--	17	--	nC
Q_{gd}	Gate-Drain Charge		--	9	--	nC
$t_{\text{D}(\text{on})}$	Turn-on Delay Time	$V_{\text{DD}}=30\text{V}, I_{\text{D}}=30\text{A},$ $R_{\text{GEN}}=1.8\Omega,$ $V_{\text{GS}}=10\text{V}$	--	15	--	ns
t_r	Turn-on Rise Time		--	80	--	ns
$t_{\text{D}(\text{off})}$	Turn-off Delay Time		--	55	--	ns
t_f	Turn-off Fall Time		--	110	--	ns
Drain-Source Diode Characteristics						
I_s	Maximum Continuous Drain-Source Diode Forward Current	--	--	55	A	
I_{SM}	Maximum Pulsed Drain-Source Diode Forward Current	--	--	230	A	
V_{SD}	Diode Forward Voltage	$I_s=30\text{A}, V_{\text{GS}}=0\text{V}$	--	--	1.2	V
t_{rr}	Reverse recovery time	$I_F=30\text{A},$ $di/dt=100 \text{ A/us}$	--	28	--	ns
Q_{rr}	Reverse recovery charge		--	33	--	nC

A. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

B. EAS condition: $T_J=25^\circ\text{C}$, $V_{\text{DD}}=30\text{V}$, $V_G=10\text{V}$, $R_G=25\text{ohm}$, $L=0.5\text{mH}$, $I_{\text{AS}}=22\text{A}$.

C. Pulse Test: Pulse Width $\leq 300\text{us}$, Duty cycle $\leq 0.5\%$.

D. Guaranteed by design, not subject to production testing.

Typical Characteristics

Figure 1: Power De-rating

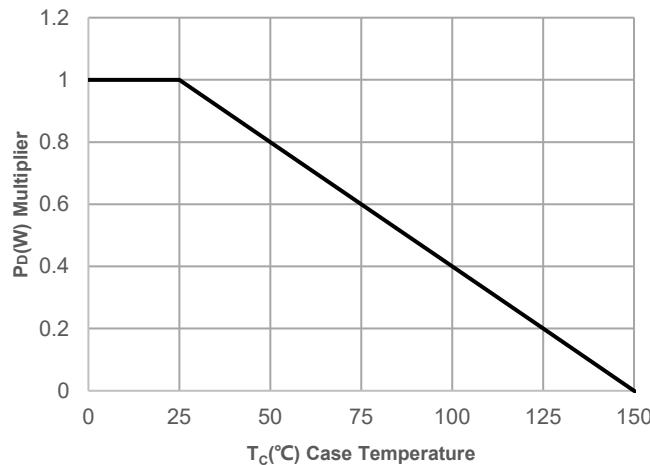


Figure 2: Current De-rating

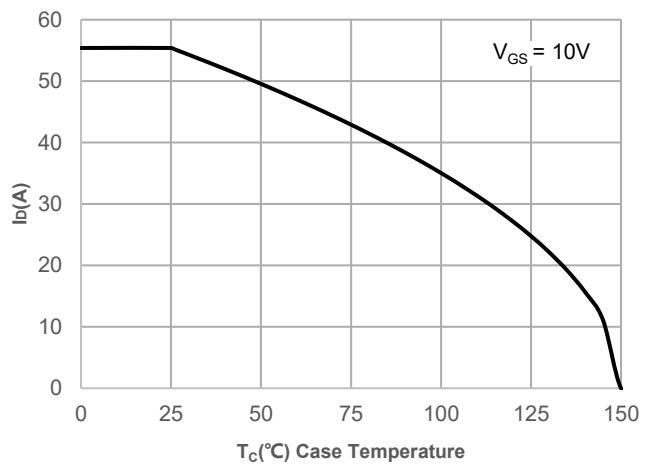


Figure 3: Normalized Maximum Transient Thermal Impedance

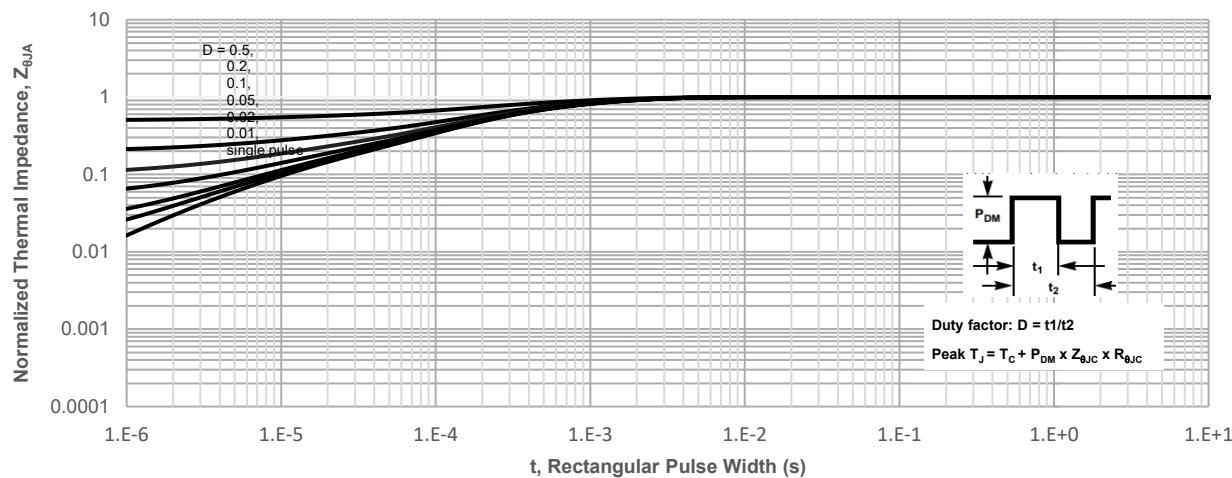
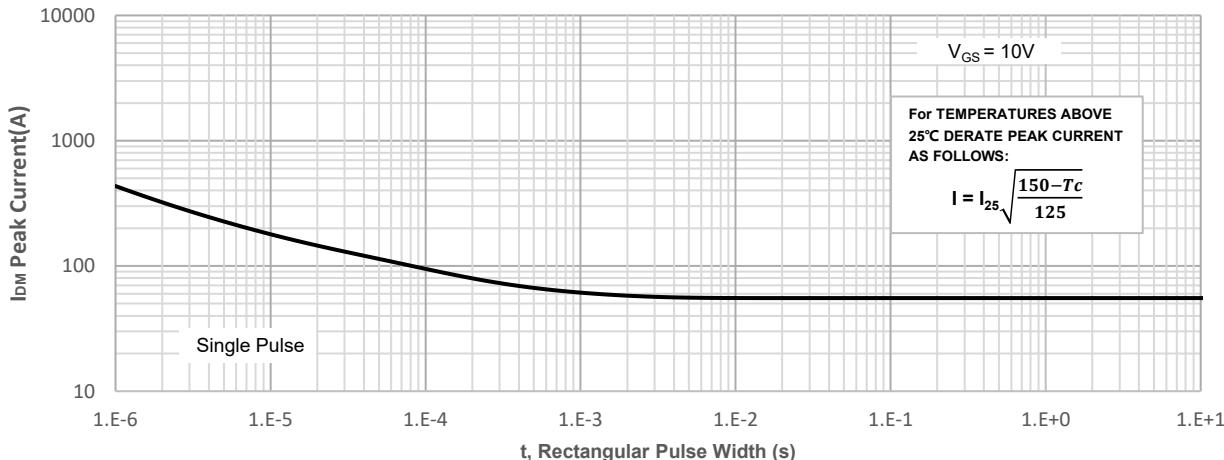


Figure 4: Peak Current Capacity



Typical Characteristics

Figure 5: Output Characteristics

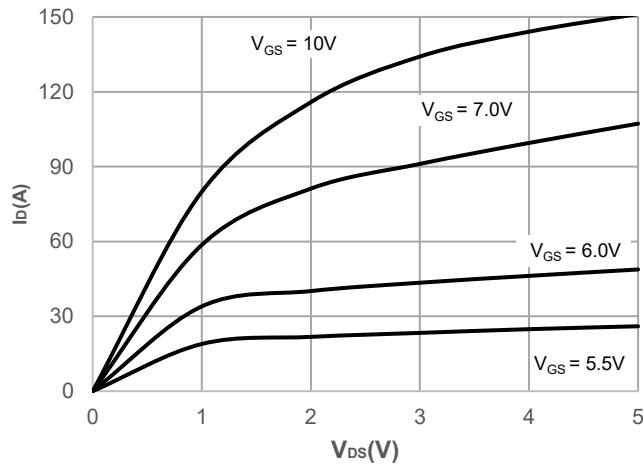


Figure 6: Typical Transfer Characteristics

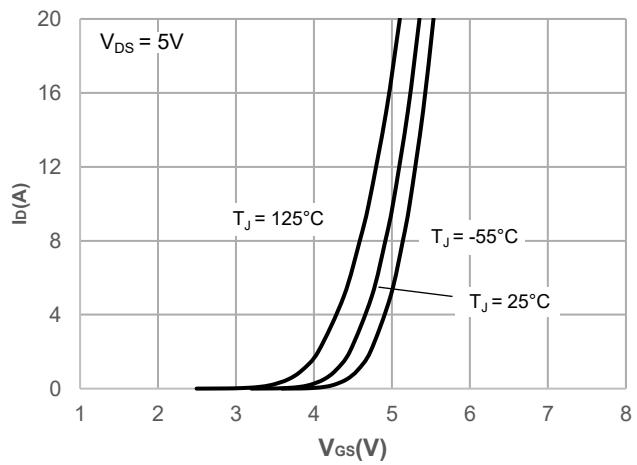


Figure 7: On-resistance vs. Drain Current

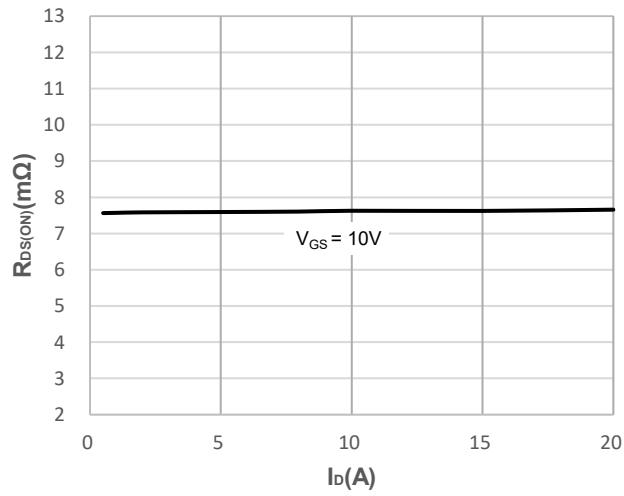


Figure 8: Body Diode Characteristics

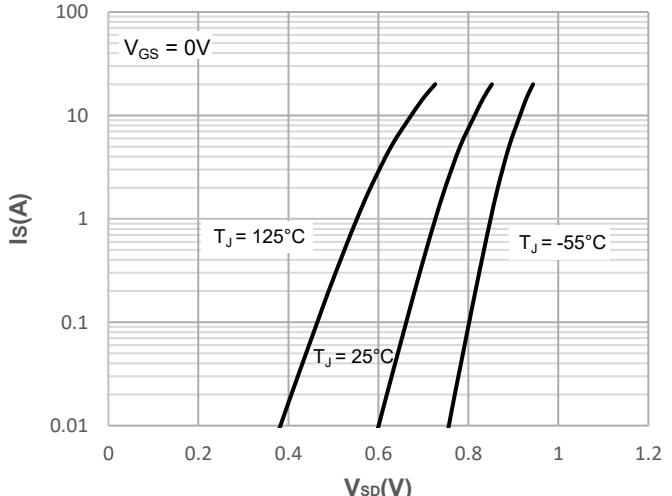


Figure 9: Gate Charge Characteristics

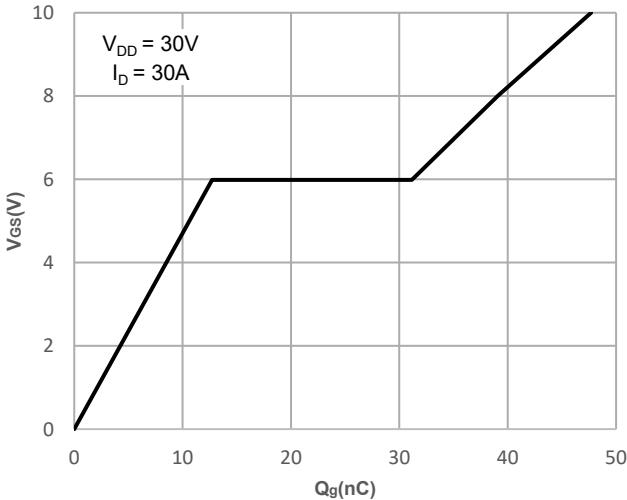
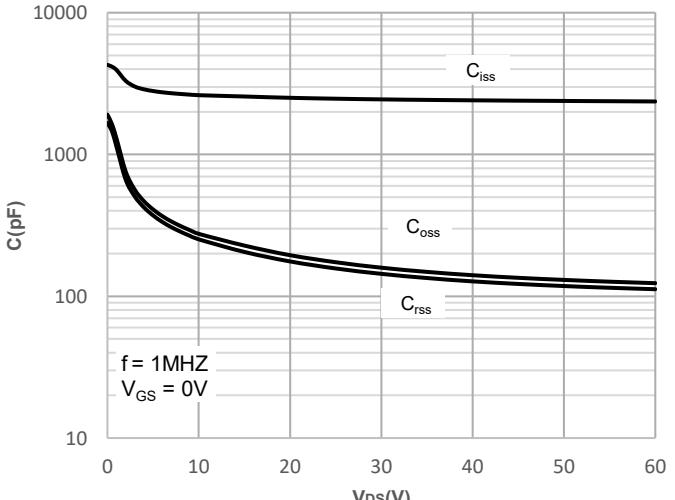


Figure 10: Capacitance Characteristics



Typical Characteristics

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

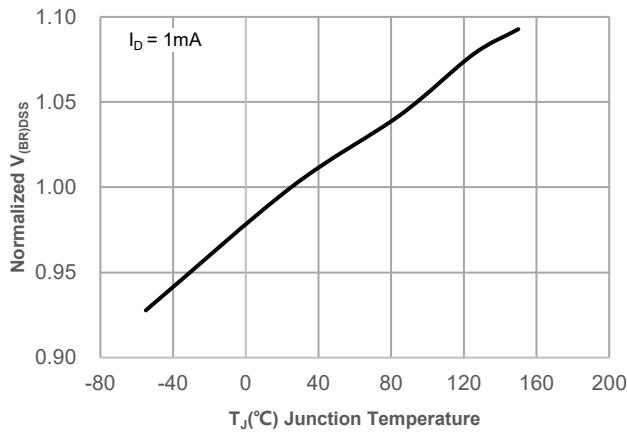


Figure 12: Normalized on Resistance vs. Junction Temperature

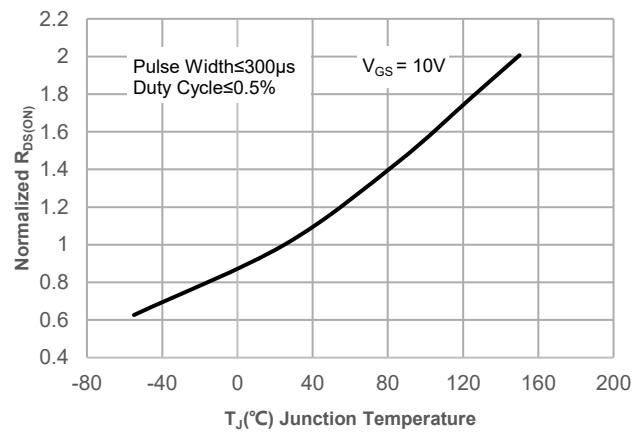


Figure 13: Normalized Threshold Voltage vs. Junction Temperature

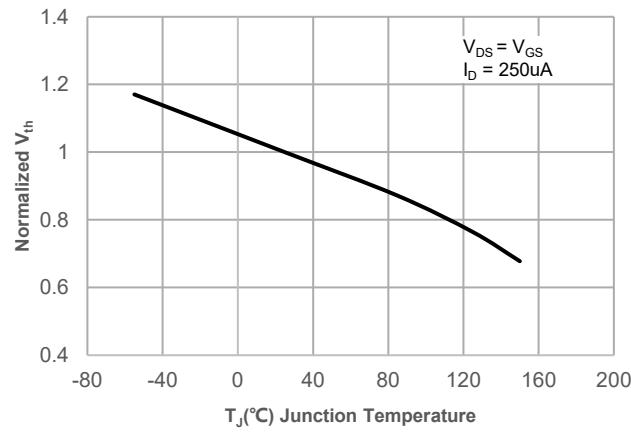


Figure 14: $R_{DS(ON)}$ vs. V_{GS}

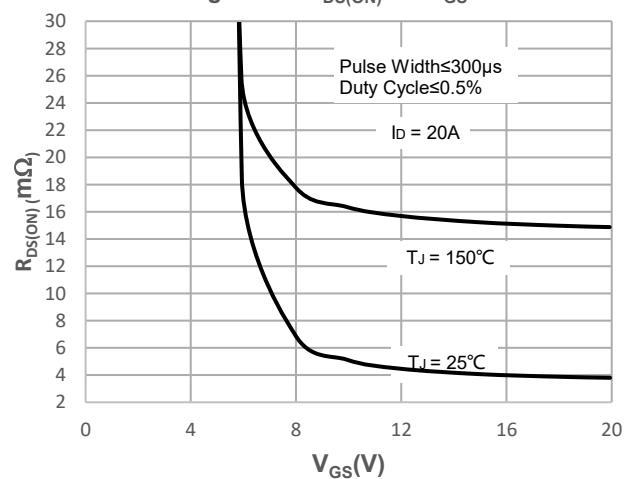
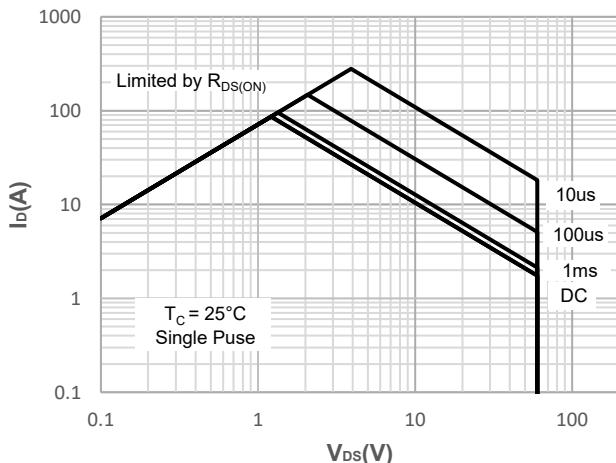


Figure 15: Maximum Safe Operating Area



Test Circuit

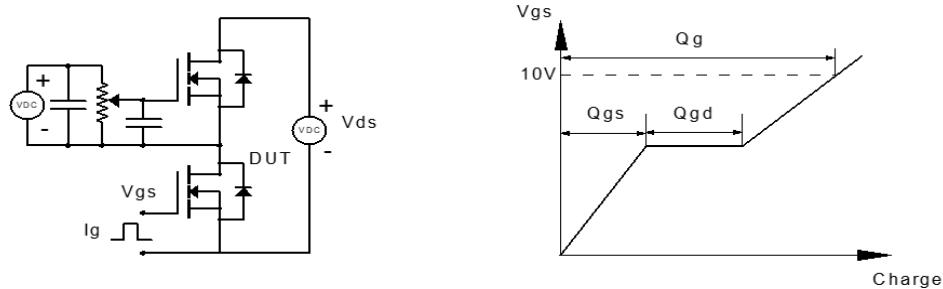


Figure 1: Gate Charge Test Circuit & Waveform

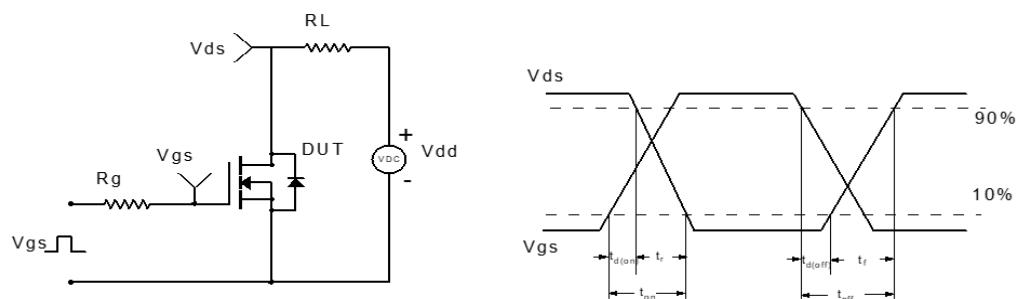


Figure 2: Resistive Switching Test Circuit & Waveform

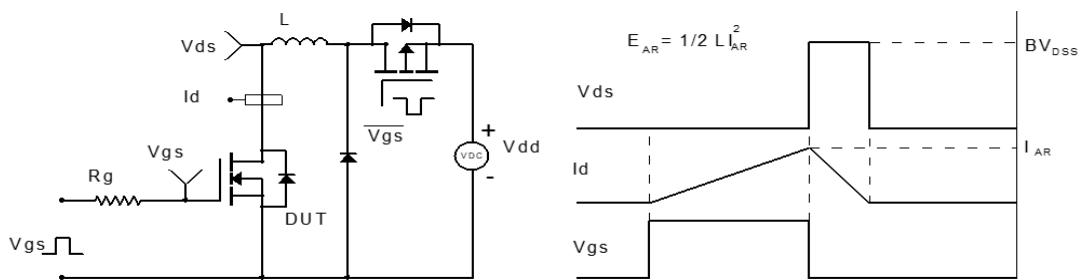


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

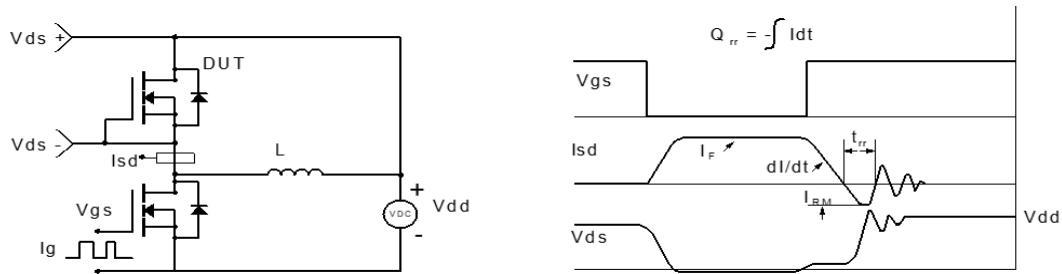
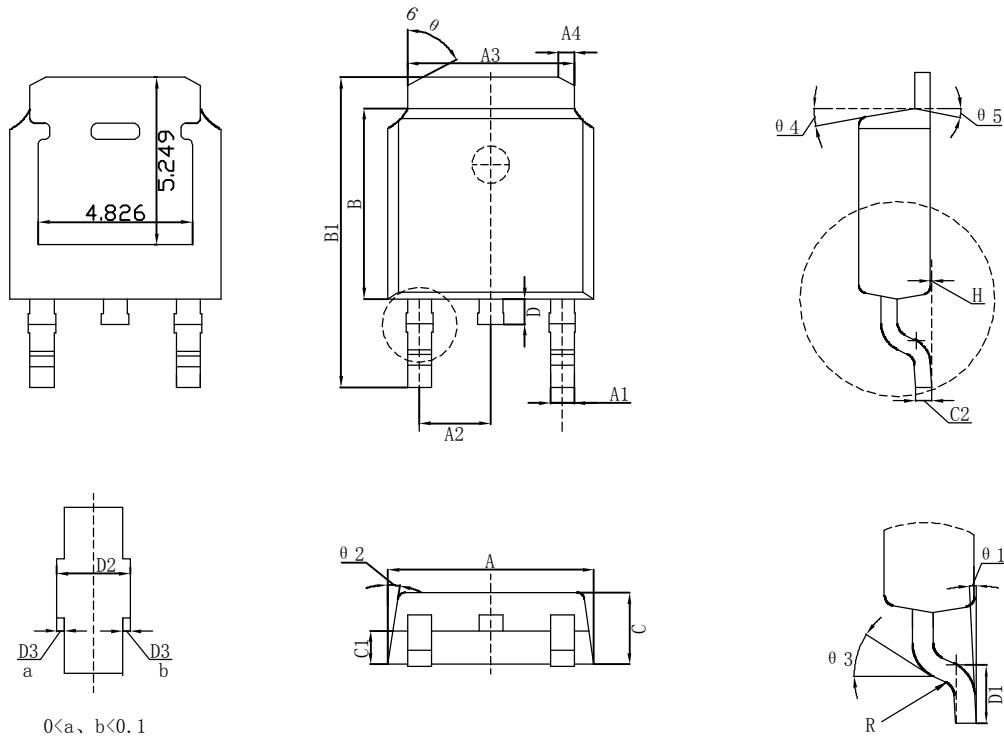


Figure 4: Diode Recovery Test Circuit & Waveform

TO-252 Package Information



标注	尺寸	最小(mm)	最大(mm)	标注	尺寸	最小(mm)	最大(mm)
A		6.50	6.70	D1		1.40	1.60
A1		0.71	0.81	D2		0.81	0.91
A2		2.236	2.336	D3		0.05TYP	
A3		5.284	5.384	H		0.00	0.10
A4		0.75	0.85	R		0.40TYP	
B		6.00	6.20	θ1		0° - 8°	
B1		9.80	10.10	θ2		8.5° TYP4	
C		2.20	2.40	θ3		25° TYP	
C1		0.967	1.087	θ4		10° TYP2	
C2		0.498	0.518	θ5		10° TYP	
D		0.70	0.90	θ6		70° TYP	